Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	der
10/760,310	HSIEH, HSIN-MAO	
Examiner	Art Unit	
Filip Zec	3744	

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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	8/4/2005	FZ
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